

AFM15

9:00 h
Xavier Obradors
(Institut de Ciència de Materials de Barcelona-ICMAB-CSIC)

Opening and introduction

9:10 h
Neus Domingo
(Institut Català de Nanociència i Nanotecnologia-ICN2)

"Electromechanical response at the nanoscale: from violins to electrical drums"

9:50 h
Andres Gómez
(Institut de Ciència de Materials de Barcelona-ICMAB-CSIC)

"Current Sensing AFM: Electrical Characterization of Materials"

10:30 h
Elena Bailo
(WITec GmbH, Barcelona)
"3D Fast Raman Imaging Meets SPM"

11:10 h
Coffe break

SALA D'ACTES ICMAB
INSTITUT DE CIÈNCIA DE
MATERIALS DE BARCELONA (CSIC)
CAMPUS UAB, BELLATERRA

11:40
Alvaro San Paulo
(Instituto de Microelectrónica de Madrid-IMM)

"Quantitative Nanomechanical Mapping Of Breast Cancer Cells By Peak Force Tapping Atomic Force Microscopy"

12:20
Pedro J. de Pablo
(Universidad Autónoma de Madrid-UAM)

"Physical virology with Atomic Force Microscopy"

13:00
Benjamín L. Holmes
(JPK Instruments AG)

"High-speed AFM imaging of soft and biological matter in liquids: challenges and results"

13:40
Lunch (not included)

15:40
Agustina Asenjo
(Instituto de Ciencia de Materiales de Madrid-ICMM)

"Nanoscale magnetism by Magnetic Force Microscopy"

16:20
Sascha Sadewasser
(Iberian Nanotechnology Laboratory-INL, Braga)

"Kelvin probe force microscopy: From atomic scale imaging to application on solar cell materials"

17:00
Gabriel Gomila
(Universitat de Barcelona, Institut de Bioenginyeria de Catalunya-UB-IBEC)

"Quantitative electrostatic force microscopy for dielectric measurements in material science and biology"

17:40-19:00
Poster session

AFM BEYOND IMAGING

NANOSCALE CHARACTERIZATION OF FUNCTIONAL MATERIALS

19th

JANUARY 2015

INSCRIPTION: www.icmab.es/afm2015

SPONSORS

JPK
Instruments

WITec
focus innovations

ASYLUM
RESEARCH
an Oxford Instruments company

ORGANIZER

ICMAB
INSTITUT DE CIÈNCIA DE MATERIALS DE BARCELONA

CSIC
CONSEJO SUPERIOR DE INVESTIGACIONES CIENTÍFICAS